

Description

The AP90N06F uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 60V I_D =90A

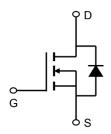
 $R_{DS(ON)} < 7.0 m\Omega \text{ @ V}_{GS} = 10 \text{V (Type: } 5.8 \text{m}\Omega)$

Application

Battery protection

Load switch

Uninterruptible power supply







Package Marking and Ordering Information

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Product ID	Pack	Marking	Qty(PCS)
AP90N06F	TO-220F-3L	AP90N06F XXX YYYY	1000

Absolute Maximum Ratings@T_i=25°C(unless otherwise specified)

Symbol	Parameter	Value	Unit
VDS	Drain source voltage	60	V
VGS	Gate source voltage	±20	V
ID	Continuous drain current¹) 90		A
IDM	Pulsed drain current ²⁾	320	A
ls	Diode forward current	37	A
ISP	Pulsed source current	210	A
P _D	Power dissipation	108	W
EAS	Single pulsed avalanche energy)	205.4	mJ
Tstg, Tj	Operation and storage temperature	-55 to 150	°C
RθJC	Thermal resistance, junction-case	1.4	°C/W
RθJA	Thermal resistance, junction-ambient ⁴⁾	62	°C/W



Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	60	64	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2	3	4	V
RDS(on)	Static Drain-Source on-Resistance note	V _{GS} =10V, I _D =30A	-	5.8	7.0	mΩ
C _{iss}	Input Capacitance	.,	-	4136	-	pF
Coss	Output Capacitance	V_{DS} =30V, V_{GS} =0V, f =1.0MHz	-	286	-	pF
Crss	Reverse Transfer Capacitance		-	257	-	pF
Qg	Total Gate Charge	V _{DS} =30V, I _D =30A,	-	90	-	nC
Q _{gs}	Gate-Source Charge	V _{GS} =10V	-	9	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	18	-	nC
td(on)	Turn-on Delay Time		-	9	-	ns
t _r	Turn-on Rise Time	V _{DS} =30V, I _D =30A,	-	7	-	ns
td(off)	Turn-off Delay Time	$R_G=1.8\Omega$, $V_{GS}=10V$	-	40	-	ns
t _f	Turn-off Fall Time		-	15	-	ns
IS	Maximum Continuous Drain to Source Diode ForwardCurrent		-	-	80	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	ı	320	Α
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	1 -204 -41/44-4064/	-	33	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F =30A, dI/dt=100A/μs	-	46	-	nC

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3. The test cond \leq 300us duty cycle \leq 2%, duty cycle ition is TJ =25 $^{\circ}$ C, VDD =35V, VG =10V, R G =25 Ω , L=0.5mH, IAS =21A
- 4. The power dissipation is limited by 175℃ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



ID (A)

Electrical Characteristics Diagrams

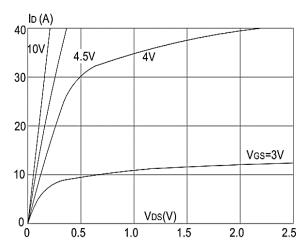


Figure1: Output Characteristics

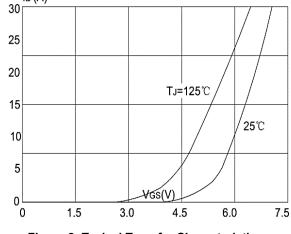


Figure 2: Typical Transfer Characteristics

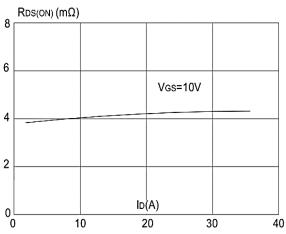


Figure 3:On-resistance vs. Drain Current

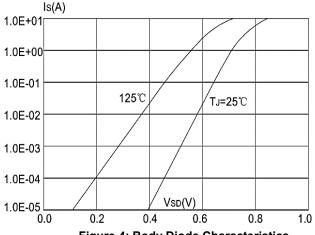


Figure 4: Body Diode Characteristics

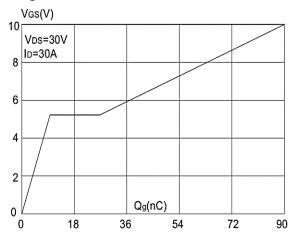


Figure 5: Gate Charge Characteristics

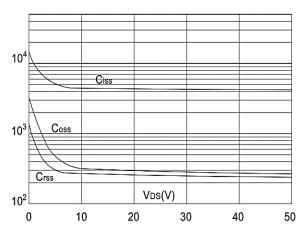


Figure 6: Capacitance Characteristics



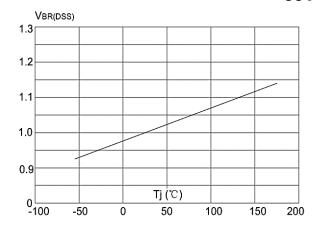


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

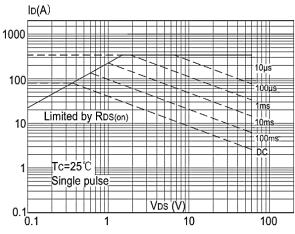


Figure 9: Maximum Safe Operating Area

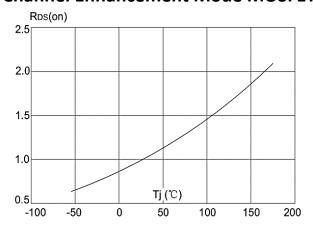


Figure 8: Normalized on Resistance vs.

Junction Temperature

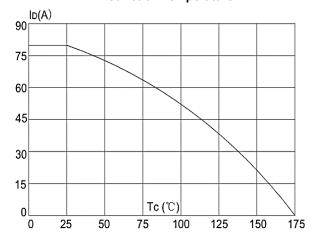


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

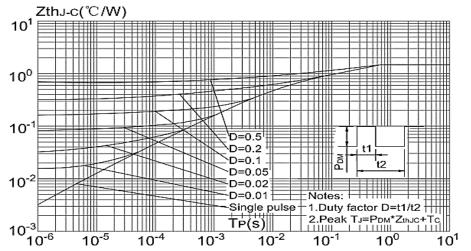
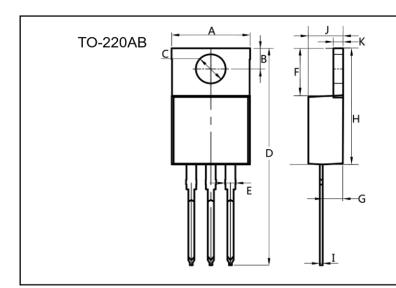
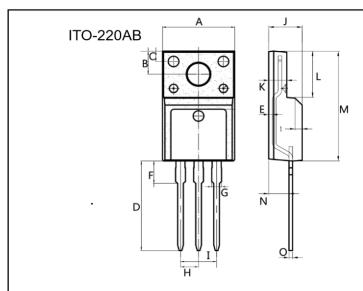


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

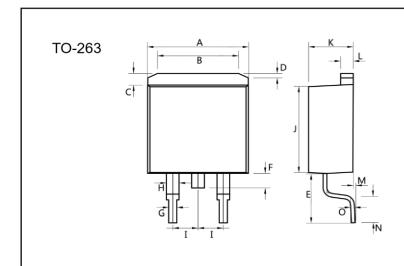




Dim.	Min.	Max.
Α	10.0	10.4
В	2.5	3.0
С	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
Н	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4
All Dimensions in millimeter		



Dim.	Min.	Max.	
Α	9.9	10.3	
В	2.9	3.5	
С	1.15	1.45	
D	12.75	13.25	
E	0.55	0.75	
F	3.1	3.5	
G	1.25	1.45	
Н	Typ 2.54		
I	Typ 5.08		
J	4.55	4.75	
K	2.4	2. 7	
L	6.35 6.75		
М	15.0	16.0	
N	2.75	3.15	
0	0.45	0.60	
All Dimensions in millimeter			



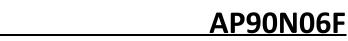
10.0 7.25 1.3	10. 5 7.75 1.5	
1.3		
	1.5	
0.55		
0.55	0.75	
5.0	6.0	
1.4	1.6	
0.75	0.95	
1.15	1.35	
Typ 2.54		
8.4	8.6	
4.4	4.6	
1.25	1.45	
0.02	0.1	
2.4	2.8	
0.35	0.45	
All Dimensions in millimeter		
	1.4 0.75 1.15 Typ 8.4 4.4 1.25 0.02 2.4 0.35	



60V N-Channel Enhancement Mode MOSFET Attention

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Edition	Date	Change
Rve1.0	2020/7/15	Initial release

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